

LTC3806EDE#PBF | [Data Sheet](#)

Qualification Summary:

STRESS TEST	TEST CONDITIONS ^{*1}	REFERENCE TEST METHOD	NUMBER OF LOTS	SAMPLE SIZE PER LOT	RESULTS
High-Temperature Operating Life (HTOL)	$T_J \geq 125^{\circ}\text{C}$, 1000 hrs	JESD22-A108	3	77	Pass
High-Temperature Storage Life (HTSL)	$T_A \geq 150^{\circ}\text{C}$, 1000 hrs	JESD22-A103	3	25	Pass
MSL Preconditioning	Per MSL	J-STD-020 JESD22-A113	—	—	Classification
Temperature Cycling (TC)	-65°C to $+150^{\circ}\text{C}$, 500 cycles	JESD22-A104	3	25	Pass
Temperature Humidity Bias (THB) or Biased HAST (HAST)	$85^{\circ}\text{C}/85\%\text{RH}$, 1000 hrs or $130^{\circ}\text{C}/85\%\text{RH}$, 96 hrs, respectively	JESD22-A101 or JESD22-A110, respectively	3	25	Pass
Autoclave (AC) or Unbiased HAST (UHAST)	$121^{\circ}\text{C}/100\%\text{RH}$, 96 hrs or $130^{\circ}\text{C}/85\%\text{RH}$, 96 hrs, respectively	JESD22-A102, JESD22-A118, respectively	3	25	Pass
ESD Human Body Model (HBM)	$T_A = 25^{\circ}\text{C}$	JS-001	1	3	See Data Sheet/ Contact Us
ESD Charge Device Model (CDM)	$T_A = 25^{\circ}\text{C}$	JS-002	1	3	See Data Sheet/ Contact Us
Latch-Up	Per JESD78	JESD78	1	3	Pass

1. Or equivalent JEDEC conditions

For FIT/ MTTF estimates, visit [FIT/ MTTF](#)

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